ADC10080 10-Bit, 80 MSPS, 3V, 78.6 mW A/D Converter

Check for Samples: ADC10080

FEATURES

- **Single +3.0V operation**
- **Selectable full-scale input swing**
- **400 MHz −3 dB input bandwidth**
- **Low power consumption**
- **Standby mode**
- **On-chip reference and sample-and-hold amplifier**
- **Offset binary or two's complement data format**
- **Separate adjustable output driver supply**

APPLICATIONS

- **Ultrasound and Imaging**
- **Instrumentation**
- **Cellular Base Stations/Communications Receivers**
- **Sonar/Radar**
- **xDSL**
- **Wireless Local Loops**
- **Data Acquisition Systems**
- **DSP Front Ends**

DESCRIPTION

The ADC10080 is a monolithic CMOS analog-to-digital converter capable of converting analog input signals into 10-bit digital words at 80 Megasamples per second (MSPS). This converter uses a differential, pipeline architecture with digital error correction and an on-chip sample-and-hold circuit to provide a complete conversion solution and to minimize power consumption, while providing excellent dynamic performance. A unique sample-and-hold stage yields a full-power bandwidth of 400 MHz. Operating on a single 3.0V power supply, this device consumes just 78.6 mW at 80 MSPS, including the reference current. The Standby feature reduces power consumption to just 15 mW.

The differential inputs provide a full scale selectable input swing of 2.0 V_{P-P}, 1.5 V_{P-P}, 1.0 V_{P-P}, with the possibility of a single-ended input. Full use of the differential input is recommended for optimum performance. An internal +1.2V precision bandgap reference is used to set the ADC full-scale range, and also allows the user to supply a buffered referenced voltage for those applications requiring increased accuracy. The output data format is user choice of offset binary or two's complement.

This device is available in the 28-lead TSSOP package and will operate over the industrial temperature range of −40°C to +85°C.

Table 1. Key Specifications

	VALUE	UNIT
Resolution	10	Bits
Conversion Rate	80	MSPS
Full Power Bandwidth	400	MHz
DNL	±0.25	LSB (typ)
SNR (f_{IN} = 10 MHz)	59.5	dB (typ)
SFDR (f_{IN} = 10 MHz)	−78.7	dB (typ)
Power Consumption, 80 Msps	78.6	mW

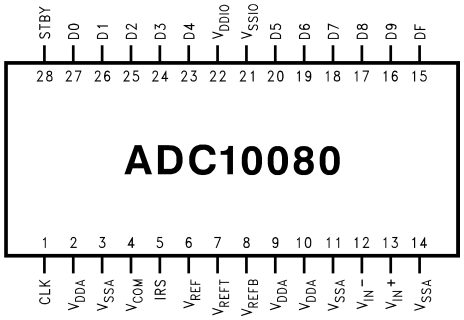
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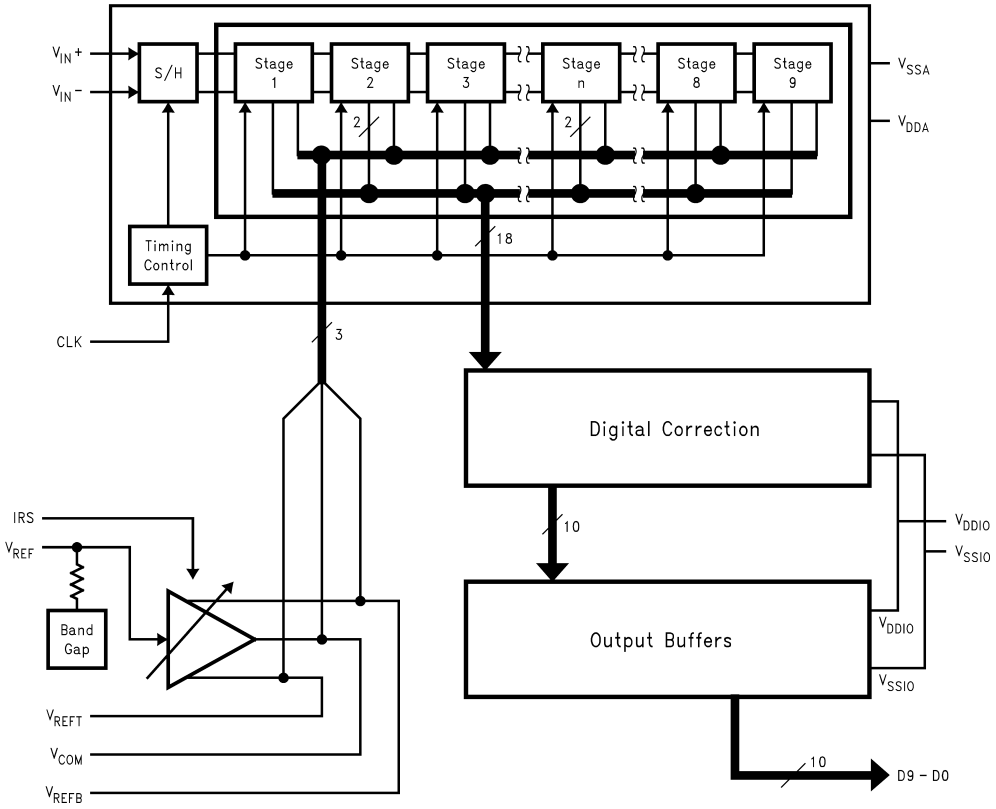
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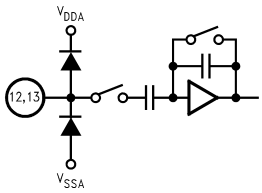
Connection Diagram



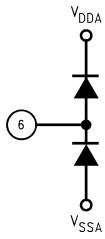
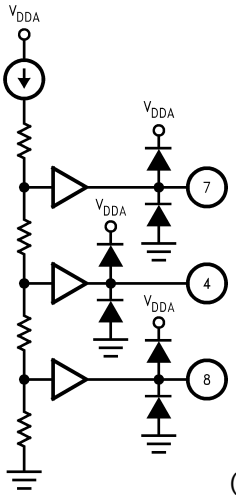
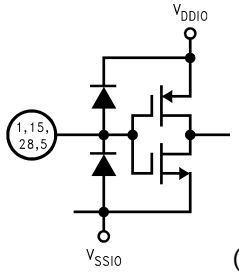
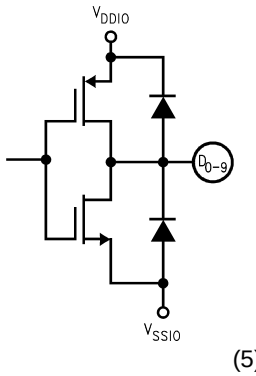
Block Diagram



Pin Descriptions and Equivalent Circuits

Pin No.	Symbol	Equivalent Circuit	Description
ANALOG I/O			
12	V_{IN}^-	 (1)	Inverting analog input signal. With a 1.2V reference the full-scale input signal level is a differential 1.0 V_{P-P}. This pin may be tied to V_{COM} (pin 4) for single-ended operation.
13	V_{IN}^+		Non-inverting analog input signal. With a 1.2V reference the full-scale input signal level is a differential 1.0 V_{P-P}.

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Pin No.	Symbol	Equivalent Circuit	Description
6	V_{REF}	 (2)	Reference input. This pin should be bypassed to V_{SSA} with a 0.1 µF monolithic capacitor. V_{REF} is 1.20V nominal. This pin may be driven by a 1.20V external reference if desired. Do not load this pin.
7	V_{REFT}	 (3)	
4	V_{COM}		These pins are high impedance reference bypass pins only. Connect a 0.1 µF capacitor from each of these pins to V_{SSA}. These pins should not be loaded. V_{COM} may be used to set the input common input voltage, V_{CM}.
8	V_{REFB}		
DIGITAL I/O			
1	CLK	 (4)	Digital clock input. The range of frequencies for this input is 20 MHz to 80 MHz. The input is sampled on the rising edge of this input.
15	DF		DF = “1” Two’s Complement DF = “0” Offset Binary
28	STBY		This is the standby pin. When high, this pin sets the converter into standby mode. When this pin is low, the converter is in active mode.
5	IRS (Input Range Select)		IRS = “V_{DDA}” 2.0 V_{P-P} differential input range IRS = “V_{SSA}” 1.5 V_{P-P} differential input range IRS = “Floating” 1.0 V_{P-P} differential input range If using both V_{IN}+ and V_{IN}- pins, (or differential mode), then the peak-to-peak voltage refers to the differential voltage (V_{IN}+ - V_{IN}-).
16–20, 23–27	D0–D9	 (5)	Digital output data. D0 is the LSB and D9 is the MSB of the binary output word.
ANALOG POWER			
2, 9, 10	V_{DDA}		Positive analog supply pins. These pins should be connected to a quiet 3.0V source and bypassed to analog ground with a 0.1 µF monolithic capacitor located within 1 cm of these pins. A 4.7 µF capacitor should also be used in parallel.
3, 11, 14	V_{SSA}		Ground return for the analog supply.
DIGITAL POWER			

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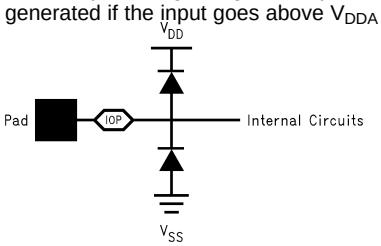
Pin No.	Symbol	Equivalent Circuit	Description
22	V_{DDIO}		Positive digital supply pins for the ADC10080's output drivers. This pin should be bypassed to digital ground with a 0.1 µF monolithic capacitor located within 1 cm of this pin. A 4.7 µF capacitor should also be used in parallel. The voltage on this pin should never exceed the voltage on V_{DDA} by more than 300 mV.
21	V_{SSIO}		The ground return for the digital supply for the output drivers. This pin should be connected to the ground plane, but not near the analog circuitry.

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings (1) (2)

V_{DDA}, V_{DDIO}	3.9V
Voltage on Any Pin to GND	−0.3V to V_{DDA} or V_{DDIO} +0.3V
Input Current on Any Pin	±25 mA
Package Input Current (3)	±50 mA
Package Dissipation at T = 25°C	See (4)
ESD Susceptibility	
Human Body Model (5)	2500V
Machine Model (5)	250V
Soldering Temperature Infrared, 10 sec. (6)	235°C
Storage Temperature	−65°C to +150°C

(1) All voltages are measured with respect to GND = V_{SSA} = V_{SSIO} = 0V, unless otherwise specified.
(2) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.
(3) When the voltage at any pin exceeds the power supplies (V_{IN} < V_{SSA} or V_{IN} > V_{DDA}), the current at that pin should be limited to 25 mA. The 50 mA maximum package input current rating limits the number of pins that can safely exceed the power supplies with an input current of 25 mA to two.
(4) The absolute maximum junction temperature ($T_J$max) for this device is 150°C. The maximum allowable power dissipation is dictated by $T_J$max, the junction-to-ambient thermal resistance (θ_{JA}), and the ambient temperature (T_A), and can be calculated using the formula P_DMAX = ($T_J$max − T_A)/θ_{JA}. In the 28-pin TSSOP, θ_{JA} is 96°C/W, so P_DMAX = 1,302 mW at 25°C and 677 mW at the maximum operating ambient temperature of 85°C. Note that the power dissipation of this device under normal operation will typically be about 78.6 mW. The values for maximum power dissipation listed above will be reached only when the ADC10080 is operated in a severe fault condition.
(5) Human body model is 100 pF capacitor discharged through a 1.5 kΩ resistor. Machine model is 220 pF discharged through 0Ω.
(6) The 235°C reflow temperature refers to infrared reflow. For Vapor Phase Reflow (VPR) the following conditions apply: Maintain the temperature at the top of the package body above 183°C for a minimum of 60 seconds. The temperature measured on the package body must not exceed 220°C. Only one excursion above 183°C is allowed per reflow cycle. The analog inputs are protected as shown below. Input voltage magnitude up to 500 mV beyond the supply rails will not damage this device. However, input errors will be generated if the input goes above V_{DDA} or V_{DDIO} and below V_{SSA} or V_{SSIO}.



Operating Ratings (1) (2)

Operating Temperature Range	−40°C ≤ T_A ≤ +85°C
V_{DDA} (Supply Voltage)	+2.7V to +3.6V

(1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.
(2) All voltages are measured with respect to GND = V_{SSA} = V_{SSIO} = 0V, unless otherwise specified.

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Operating Ratings (1) (2) (continued)

V_{DDIO} (Output Driver Supply Voltage)	+2.5V to V_{DDA}
V_{REF}	1.20V
$\lvert V_{SSA} - V_{SSIO} \rvert$	≤ 100 mV
Clock Duty Cycle	30 to 70 %

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Converter Electrical Characteristics

Unless otherwise specified, the following specifications apply for V_{SSA} = V_{SSIO} = 0V[(1) (1) (2)], V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.20V (External), f_{CLK} = 80 MHz, 50% Duty Cycle, C_L = 10 pF/pin. **Boldface limits apply for T_A = T_{MIN} to T_{MAX}:** all other limits T_A = 25°C.[(3) (1) (2)]

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC CONVERTER CHARACTERISTICS						
	No Missing Codes Guaranteed		**10**			Bits
INL	Integral Non-Linearity [(4)]	F_{IN} = 500 kHz, 0 dB Full Scale	**−1.4**	±0.5	**+1.6**	LSB
DNL	Differential Non-Linearity	F_{IN} = 500 kHz, 0 dB Full Scale	**−0.9**	±0.25	**+1.0**	LSB
GE	Gain Error	Positive Error	**−1.6**	+0.5%	**+2.0**	% FS
		Negative Error	**−1.6**	−0.07%	**+2.0**	% FS
OE	Offset Error (V_{IN}+ = V_{IN}−)		**−1.4**	0.11	**1.7**	% FS
	Under Range Output Code			0		
	Over Range Output Code			1023		
FPBW	Full Power Bandwidth			400		MHz
REFERENCE AND INPUT CHARACTERISTICS						
V_{CM}	Common Mode Input Voltage		0.5		1.5	V
V_{COM}	Output Voltage for use as an input common mode voltage [(5)]			1.45		V
V_{REF}	Internal Reference Voltage			1.2		V
	External Reverence Voltage		1.0	1.2	1.5	V
V_{REFTC}	Internal Reference Voltage Temperature Coefficient			±80		ppm/°C
C_{IN}	V_{IN} Input Capacitance (each pin to V_{SSA})			4		pF
POWER SUPPLY CHARACTERISTICS						
I_{VDDA}	Analog Supply Current	STBY = 1		5	**6.3**	mA
		STBY 0		25	**32**	mA
I_{VDDIO}	Digital Supply Current [(6)]	STBY = 1, f_{IN}= 0 Hz		0		mA
		STBY 0, f_{IN} = 0 Hz		1.2	**1.4**	mA
PWR	Power Consumption [(7)]	STBY = 1		15	**18.9**	mW
		STBY = 0		78.6	**100.2**	mW

(1) With the test condition for 2 V_{P-P} differential input, the 10-bit LSB is 1.95 mV.
(2) Typical figures are at T_A = T_J = 25°C and represent most likely parametric norms. Test limits are guaranteed to National's AOQL (Average Outgoing Quality Level).
(3) To guarantee accuracy, it is required that $|V_{DDA}–V_{DDIO}| \le 100$ mV and separate bypass capacitors are used at each power supply pin.
(4) Timing specifications are tested at TTL logic levels, V_{IL} = 0.4V for a falling edge, and V_{IH} = 2.4V for a rising edge.
(5) V_{COM} is typical value, measured at room temperature. It is not guaranteed by test. This pin should not be loaded.
(6) I_{VDDIO} is the current consumed by the switching of the output drivers and is primarily determined by load capacitance on the output pins, the supply voltage, V_{DDIO}, and the rate at which the outputs are switching (which is signal dependent). I_{DR} = V_{DR} x (C_0 x f_0 + C_1 x f_1 + C_2 + f_2 +....C_{11} x f_{11}) where V_{DR} is the output driver supply voltage, C_n is the total load capacitance on the output pin, and f_n is the average frequency at which the pin is toggling.
(7) Power consumption includes output driver power. (f_{IN} = 0 MHz).

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DC and Logic Electrical Characteristics

Unless otherwise specified, the following specifications apply for V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.20V (External), f_{CLK} = 80 MHz, 50% Duty Cycle, C_L = 10 pF/pin. **Boldface limits apply for T_A = T_{MIN} to T_{MAX}:** all other limits T_A = 25°C (1) (2) (3)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
CLK, DF, STBY, SENSE						
	Logical “1” Input Voltage		**2**			V
	Logical “0” Input Voltage				**0.8**	V
	Logical “1” Input Current				**+10**	µA
	Logical “0” Input Current		**−10**			µA
D0–D9 OUTPUT CHARACTERISTICS						
	Logical “1” Output Voltage	I_{OUT} = −0.5 mA	**V_{DDIO}−0.2**			V
	Logical “0” Output Voltage	I_{OUT} = 1.6 mA			**0.4**	V
DYNAMIC CONVERTER CHARACTERISTICS (4)						
ENOB	Effective Number of Bits	f_{IN} = 10.0 MHz	9.3 **9.1**	9.5		Bits
		f_{IN} = 39 MHz	9.3 **8.9**	9.5		Bits
SNR	Signal-to-Noise Ratio	f_{IN} = 10.0 MHz	58.5 **57.7**	59.5		dB
		f_{IN} = 39 MHz	58.0 **57.0**	59.2		dB
SINAD	Signal-to-Noise Ratio + Distortion	f_{IN} = 10.0 MHz	58.0 **56.3**	59.2		dB
		f_{IN} = 39 MHz	57.6 **55.6**	59.0		dB
2nd HD	2nd Harmonic	f_{IN} = 10.0 MHz	−74.1 **−68.7**	−87.0		dBc
		f_{IN} = 39 MHz	−69.5 **−62.7**	−82		dBc
3rd HD	3rd Harmonic	f_{IN} = 10.0 MHz	−65 **−58.6**	−72.3		dBc
		f_{IN} = 39 MHz	−64.7 **−57.6**	−74.5		dBc
THD	Total Harmonic Distortion (First 6 Harmonics)	f_{IN} = 10.0 MHz	−65 **−58.6**	−72.3		dB
		f_{IN} = 39 MHz	−64.7 **−57.6**	−74.5		dB
SFDR	Spurious Free Dynamic Range (Excluding 2nd and 3rd Harmonic)	f_{IN} = 10.0 MHz	−70.8 **−68.2**	−78.7		dBc
		f_{IN} = 39 MHz	−72 **−68**	−78.8		dBc

(1) To guarantee accuracy, it is required that $|V_{DDA}–V_{DDIO}| \le 100$ mV and separate bypass capacitors are used at each power supply pin.
(2) With the test condition for 2 V_{P-P} differential input, the 10-bit LSB is 1.95 mV.
(3) Typical figures are at T_A = T_J = 25°C and represent most likely parametric norms. Test limits are guaranteed to National's AOQL (Average Outgoing Quality Level).
(4) Optimum dynamic performance will be obtained by keeping the reference input at +1.2V.

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AC Electrical Characteristics

Unless otherwise specified, the following specifications apply for V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.20V, (Externally Supplied) f_{CLK} = 80 MHz, 50% Duty Cycle, C_L = 10 pF/pin. **Boldface limits apply for T_A = T_{MIN} to T_{MAX}:** all other limits T_A = 25°C (1) (2) (3) (4)

Symbol	Parameter	Conditions	Min (4)	Typ (4)	Max (4)	Units
CLK, DF, STBY, SENSE						
$f_{CLK}1$	Maximum Clock Frequency				80	MHz (min)
$f_{CLK}2$	Minimum Clock Frequency			20		MHz
t_{CH}	Clock High Time			6.25		ns
t_{CL}	Clock Low Time			6.25		ns
	Conversion Latency				**6**	Cycles
t_{OD}	Data Output Delay after a Rising Clock Edge	T = 25°C	2	3.5	5	ns
			1		**6**	ns
t_{AD}	Aperture Delay			1		ns
t_{AJ}	Aperture Jitter			2		ps (RMS)
	Over Range Recovery Time	Differential V_{IN} step from ±3V to 0V to get accurate conversion		1		Clock Cycle
t_{STBY}	Standby Mode Exit Cycle			20		Cycles

(1) To guarantee accuracy, it is required that $|V_{DDA}–V_{DDIO}|$ ≤ 100 mV and separate bypass capacitors are used at each power supply pin.
(2) With the test condition for 2 V_{P-P} differential input, the 10-bit LSB is 1.95 mV.
(3) Typical figures are at T_A = T_J = 25°C and represent most likely parametric norms. Test limits are guaranteed to National's AOQL (Average Outgoing Quality Level).
(4) Timing specifications are tested at TTL logic levels, V_{IL} = 0.4V for a falling edge, and V_{IH} = 2.4V for a rising edge.

Specification Definitions

APERTURE DELAY is the time after the rising edge of the clock to when the input signal is acquired or held for conversion.

APERTURE JITTER (APERTURE UNCERTAINTY) is the variation in aperture delay from sample to sample. Aperture jitter manifests itself as noise in the output.

COMMON MODE VOLTAGE (V_{CM}) is the d.c. potential present at both signal inputs to the ADC.

CONVERSION LATENCY See PIPELINE DELAY.

DIFFERENTIAL NON-LINEARITY (DNL) is the measure of the maximum deviation from the ideal step size of 1 LSB.

DUTY CYCLE is the ratio of the time that a repetitive digital waveform is high to the total time of one period. The specification here refers to the ADC clock input signal.

EFFECTIVE NUMBER OF BITS (ENOB, or EFFECTIVE BITS) is another method of specifying Signal-to-Noise and Distortion or SINAD. ENOB is defined as (SINAD - 1.76) / 6.02 and states that the converter is equivalent to a perfect ADC of this (ENOB) number of bits.

FULL POWER BANDWIDTH is a measure of the frequency at which the reconstructed output fundamental drops 3 dB below its low frequency value for a full scale input.

GAIN ERROR is the deviation from the ideal slope of the transfer function. It can be calculated as:

Gain Error = Positive Full-Scale Error − Negative Full-Scale Error (6)

INTEGRAL NON LINEARITY (INL) is a measure of the deviation of each individual code from a line drawn from negative full scale through positive full scale. The deviation of any given code from this straight line is measured from the center of that code value.

MISSING CODES are those output codes that will never appear at the ADC outputs. The ADC10080 is guaranteed not to have any missing codes.

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NEGATIVE FULL SCALE ERROR is the difference between the input voltage ($V_{IN}^+ - V_{IN}^-$) just causing a transition from negative full scale to the first code and its ideal value of 0.5 LSB.

OFFSET ERROR is the input voltage that will cause a transition from a code of 01 1111 1111 to a code of 10 0000 0000.

OUTPUT DELAY is the time delay after the rising edge of the clock before the data update is presented at the output pins.

PIPELINE DELAY (LATENCY) is the number of clock cycles between initiation of conversion and when that data is presented to the output driver stage. Data for any given sample is available at the output pins the Pipeline Delay plus the Output Delay after the sample is taken. New data is available at every clock cycle, but the data lags the conversion by the pipeline delay.

POSITIVE FULL SCALE ERROR is the difference between the actual last code transition and its ideal value of 1½ LSB below positive full scale.

SIGNAL TO NOISE RATIO (SNR) is the ratio, expressed in dB, of the rms value of the input signal to the rms value of the sum of all other spectral components below one-half the sampling frequency, not including harmonics or DC.

SIGNAL TO NOISE PLUS DISTORTION (S/N+D or SINAD) Is the ratio, expressed in dB, of the rms value of the input signal to the rms value of all of the other spectral components below half the clock frequency, including harmonics but excluding DC.

SPURIOUS FREE DYNAMIC RANGE (SFDR) is the difference, expressed in dB, between the rms values of the input signal and the peak spurious signal, where a spurious signal is any signal present in the output spectrum that is not present at the input.

TOTAL HARMONIC DISTORTION (THD) is the ratio, expressed in dBc, of the rms total of the first six harmonic levels at the output to the level of the fundamental at the output. THD is calculated as:

$$THD = 20 \times \log \sqrt{\frac{f_2^2 + f_3^2 + \ldots + f_6^2}{f_1^2}} \tag{7}$$

where f_1 is the RMS power of the fundamental (output) frequency and f_2 through f_6 are the RMS power in the first 6 harmonic frequencies.

Second Harmonic Distortion (2nd Harm) is the difference expressed in dB, between the RMS power in the input frequency at the output and the power in its 2nd harmonic level at the output.

Third Harmonic Distortion (3rd Harm) is the difference, expressed in dB, between the RMS power in the input frequency at the output and the power in its 3rd harmonic level at the output.

Timing Diagram

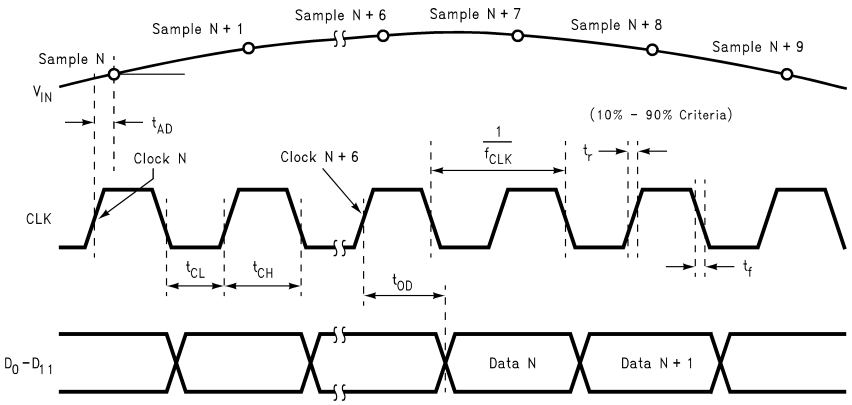


Figure 1. Clock and Data Timing Diagram

Transfer Characteristics

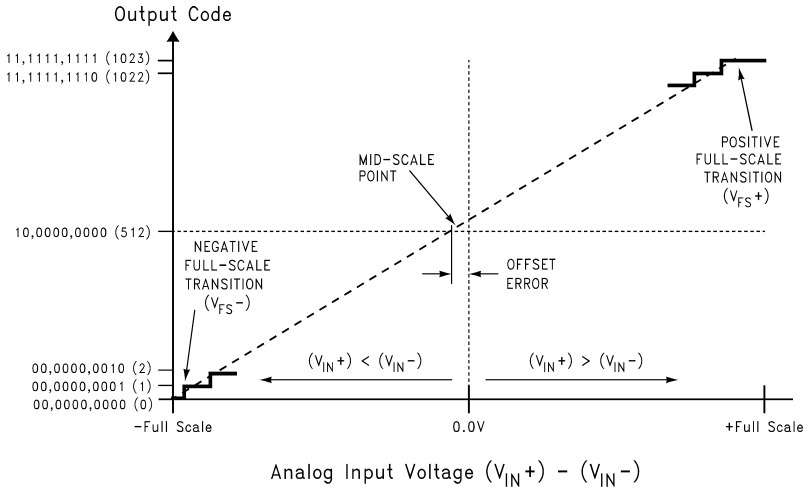


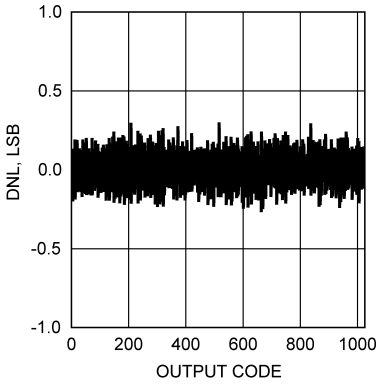
Figure 2. Input vs. Output Transfer Characteristic

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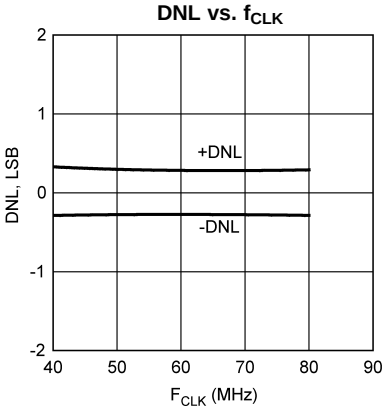
Typical Performance Characteristics

Unless otherwise specified, the following specifications apply: V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.2V (External), f_{CLK} = 80 MHz, f_{IN} , 39 MHz, 50% Duty Cycle.

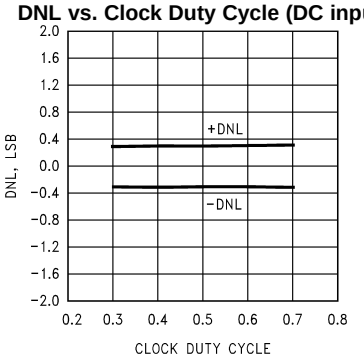
DNL



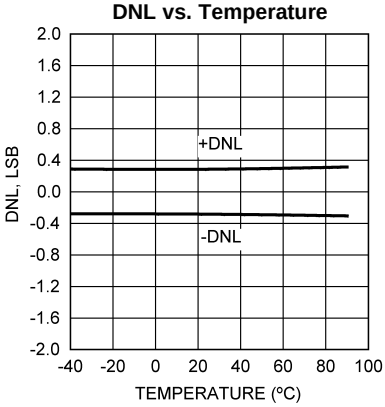
DNL vs. f_{CLK}



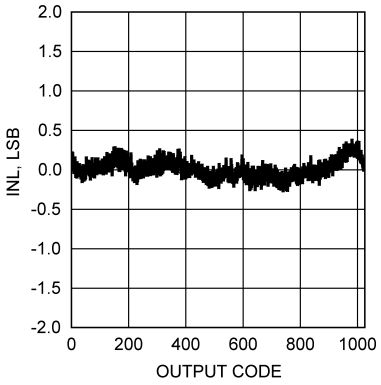
DNL vs. Clock Duty Cycle (DC input)



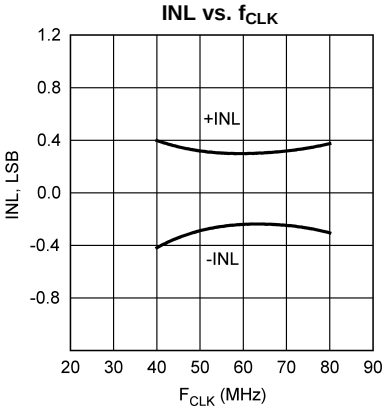
DNL vs. Temperature



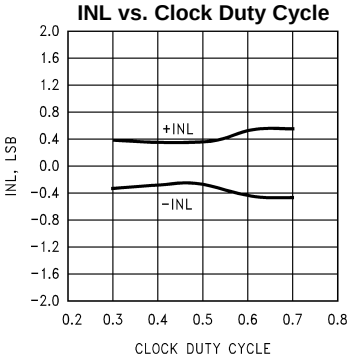
INL



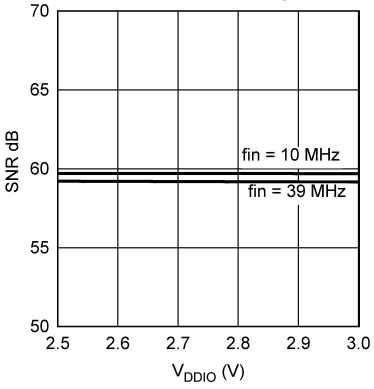
INL vs. f_{CLK}



INL vs. Clock Duty Cycle



SNR vs. V_{DDIO}

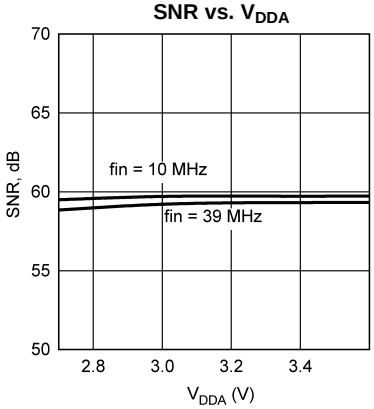


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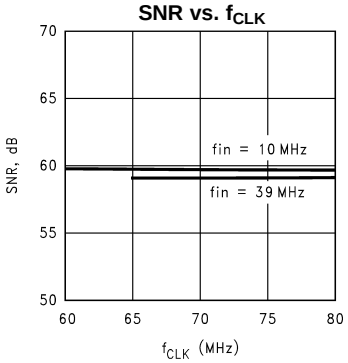
Typical Performance Characteristics (continued)

Unless otherwise specified, the following specifications apply: V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.2V (External), f_{CLK} = 80 MHz, f_{IN} , 39 MHz, 50% Duty Cycle.

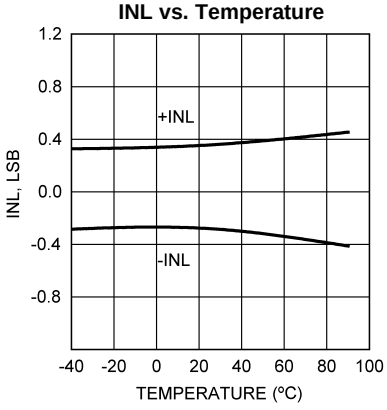
SNR vs. V_{DDA}



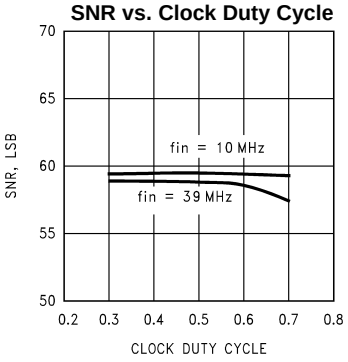
SNR vs. f_{CLK}



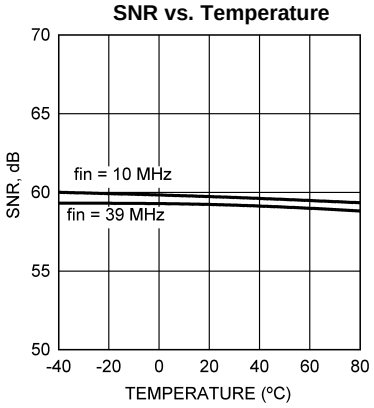
INL vs. Temperature



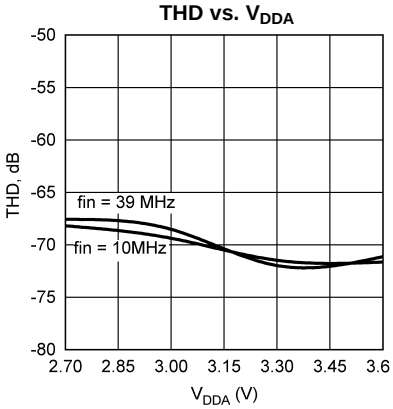
SNR vs. Clock Duty Cycle



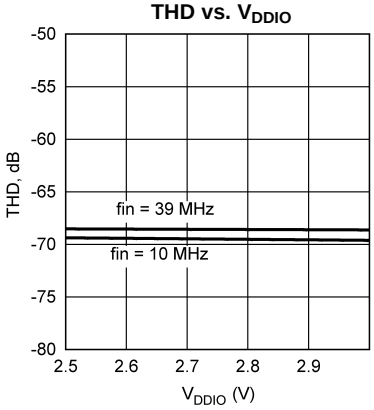
SNR vs. Temperature



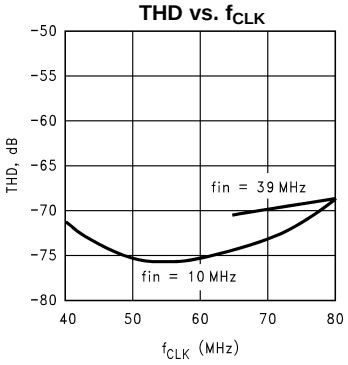
THD vs. V_{DDA}



THD vs. V_{DDIO}



THD vs. f_{CLK}

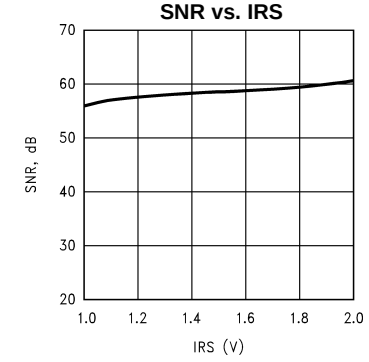


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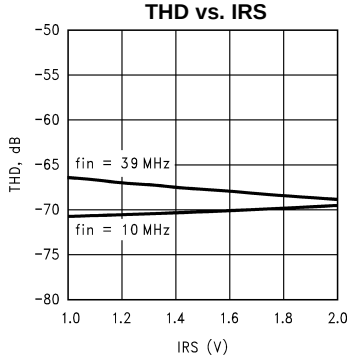
Typical Performance Characteristics (continued)

Unless otherwise specified, the following specifications apply: V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.2V (External), f_{CLK} = 80 MHz, f_{IN} , 39 MHz, 50% Duty Cycle.

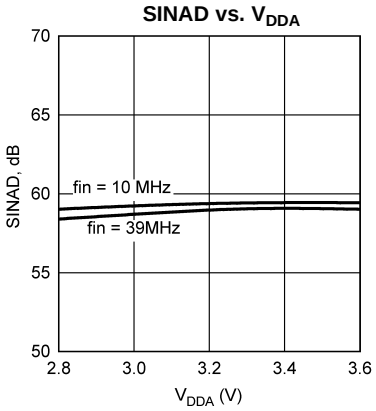
SNR vs. IRS



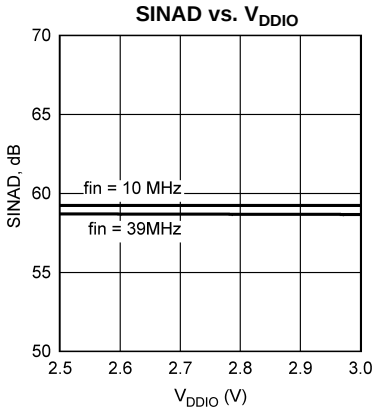
THD vs. IRS



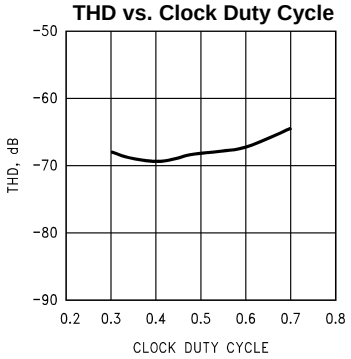
SINAD vs. V_{DDA}



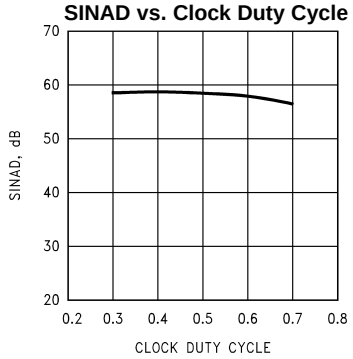
SINAD vs. V_{DDIO}



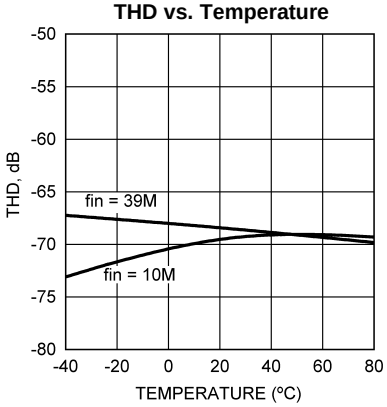
THD vs. Clock Duty Cycle



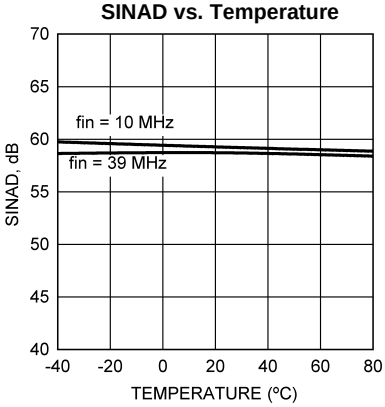
SINAD vs. Clock Duty Cycle



THD vs. Temperature



SINAD vs. Temperature

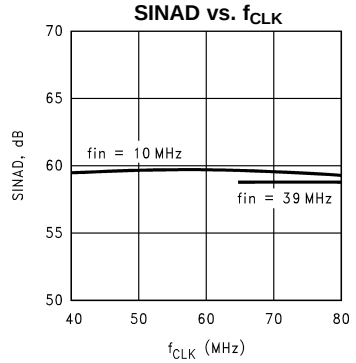


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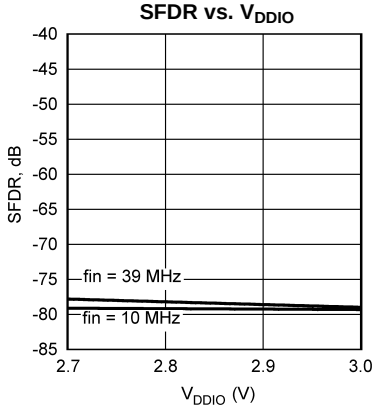
Typical Performance Characteristics (continued)

Unless otherwise specified, the following specifications apply: V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.2V (External), f_{CLK} = 80 MHz, f_{IN} , 39 MHz, 50% Duty Cycle.

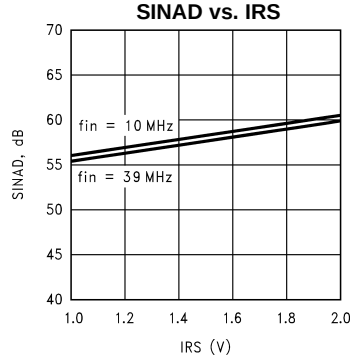
SINAD vs. f_{CLK}



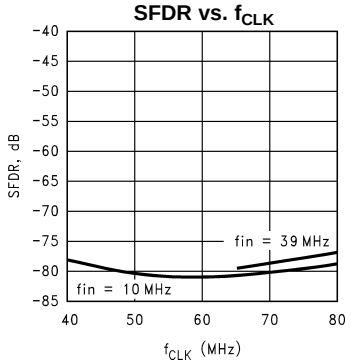
SFDR vs. V_{DDIO}



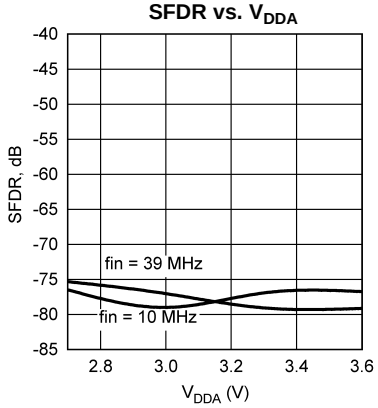
SINAD vs. IRS



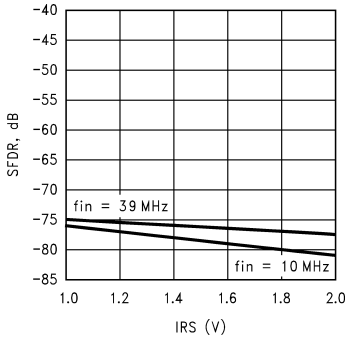
SFDR vs. f_{CLK}



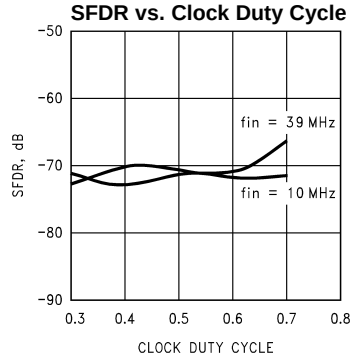
SFDR vs. V_{DDA}



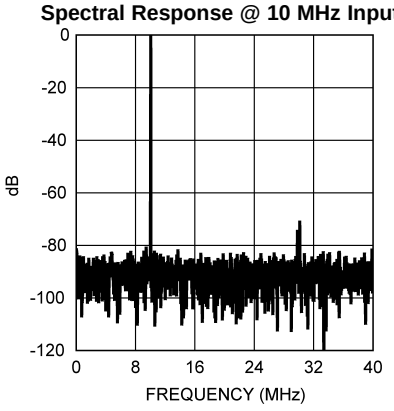
SFDR vs. IRS



SFDR vs. Clock Duty Cycle



Spectral Response @ 10 MHz Input

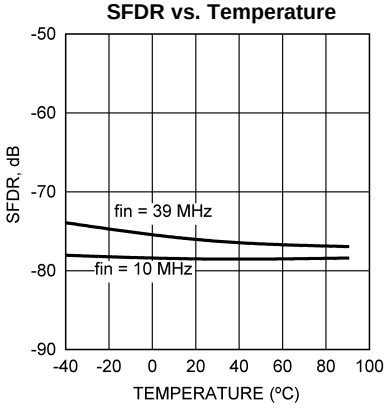


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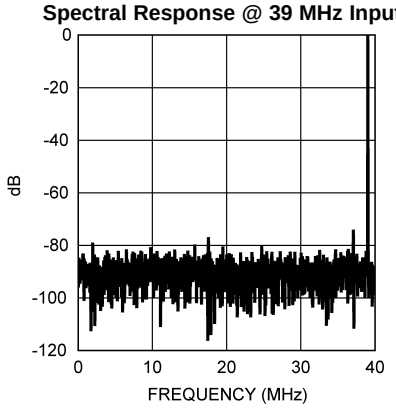
Typical Performance Characteristics (continued)

Unless otherwise specified, the following specifications apply: V_{SSA} = V_{SSIO} = 0V, V_{DDA} = +3.0V, V_{DDIO} = +2.5V, V_{IN} = 2 V_{P-P}, STBY = 0V, V_{REF} = 1.2V (External), f_{CLK} = 80 MHz, f_{IN} , 39 MHz, 50% Duty Cycle.

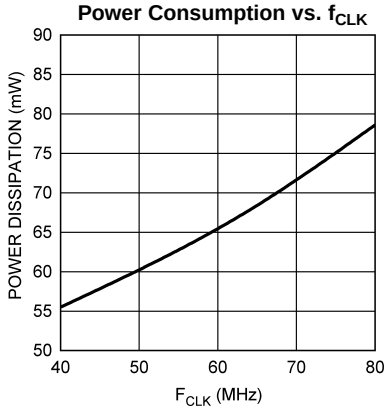
SFDR vs. Temperature



Spectral Response @ 39 MHz Input



Power Consumption vs. f_{CLK}



Functional Description

The ADC10080 uses a pipeline architecture and has error correction circuitry to help ensure maximum performance. Differential analog input signals are digitized to 10 bits. In differential mode each analog input signal should have a peak-to-peak voltage equal to 1.0V, 0.75V or 0.5V, depending on the state of the IRS pin (pin 5), and be centered around V_{CM} and be 180° out of phase with each other. If single ended operation is desired, V_{IN}- may be tied to the V_{COM} pin (pin 4). A single ended input signal may then be applied to V_{IN}+, and should have a mid range value of V_{COM}. The signal amplitude should be 2.0V, 1.5V or 1.0V peak-to-peak, depending on the state or the IRS pin (pin 5).

Applications Information

1.0 ANALOG INPUTS

The ADC10080 has two analog signal inputs, V_{IN}+ and V_{IN}−. These two pins form a differential input pair. There is one common mode pin V_{COM} that may be used to set the common mode input voltage.

1.2 V_{COM} PIN

This pin supplies a voltage for possible use to set the common mode input voltage. This pin may also be connected to V_{IN}-, so that V_{IN}+ may be used as a single ended input. This pin should be bypassed with at least a 0.1 uF capacitor. Do not load this pin.

1.3 SIGNAL INPUTS

The signal inputs are V_{IN}+ and V_{IN}−. The input signal amplitude is defined as V_{IN}+ − V_{IN}− and is represented in Figure 3*:*

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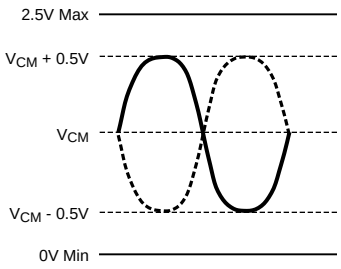


Figure 3. Input Voltage Waveforms for a $2V_{P-P}$ Differential Input

A single ended input signal is shown in Figure 4.

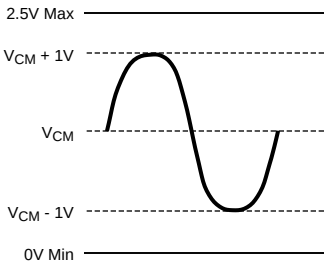


Figure 4. Input Voltage Waveform for a $2V_{P-P}$ Single Ended Input

The internal switching action at the analog inputs causes energy to be output from the input pins. As the driving source tries to compensate for this, it adds noise to the signal. To prevent this, use 18Ω series resistors at each of the signal input pins with a 25 pF capacitor across the inputs, as shown in Figure 5. These components should be placed close to the ADC because the input pins of the ADC is the most sensitive part of the system and this is the last opportunity to filter the input. The two 18Ω resistors and the 25 pF capacitor form a low-pass filter with a -3 dB frequency of 177 MHz.

1.4 CLK PIN

The CLK signal controls the timing of the sampling process. Drive the clock input with a stable, low jitter clock signal in the frequency range indicated in the AC Electrical Characteristics Table with rise and fall times of less than 2 ns. The trace carrying the clock signal should be as short as possible and should not cross any other signal line, analog or digital, not even at 90°. The CLK signal also drives an internal state machine. If the CLK is interrupted, or its frequency is too low, the charge on internal capacitors can dissipate to the point where the accuracy of the output data will degrade. This is what limits the lowest sample rate. The duty cycle of the clock

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signal can affect the performance of any A/D Converter. Because achieving a precise duty cycle is difficult, the ADC10080 is designed to maintain performance over a range of duty cycles. While it is specified and performance is guaranteed with a 50% clock duty cycle, performance is typically maintained with minimum clock low and high times indicated in the AC Electrical Characteristics Table. Both minimum high and low times may not be held simultaneously.

1.5 STBY PIN

The STBY pin, when high, holds the ADC10080 in a power-down mode to conserve power when the converter is not being used. The power consumption in this state is 15 mW. The output data pins are undefined in this mode. Power consumption during power-down is not affected by the clock frequency, or by whether there is a clock signal present. The data in the pipeline is corrupted while in power down.

1.6 DF PIN

The DF (Data Format) pin, when high, forces the ADC10080 to output the 2's complement data format. When DF is tied low, the output format is offset binary.

1.7 IRS PIN

The IRS (Input Range Select) pin defines the input signal amplitude that will produce a full scale output. The table below describes the function of the IRS pin.

Table 2. IRS Pin Functions

IRS Pin	Full-Scale Input
V_{DDA}	$2.0V_{P-P}$
V_{SSA}	$1.5V_{P-P}$
Floating	$1.0V_{P-P}$

1.8 OUTPUT PINS

The ADC10080 has 10 TTL/CMOS compatible Data Output pins. The offset binary data is present at these outputs while the DF and STBY pins are low. Be very careful when driving a high capacitance bus. The more capacitance the output drivers must charge for each conversion, the more instantaneous digital current flows through V_{DDIO} and V_{SSIO}. These large charging current spikes can cause on-chip noise and couple into the analog circuitry, degrading dynamic performance. Adequate bypassing, limiting output capacitance and careful attention to the ground plane will reduce this problem. Additionally, bus capacitance beyond the specified 10 pF/pin will cause t_{OD} to increase, making it difficult to properly latch the ADC output data. The result could be an apparent reduction in dynamic performance. To minimize noise due to output switching, minimize the load currents at the digital outputs. This can be done by minimizing load capacitance and by connecting buffers between the ADC outputs and any other circuitry, which will isolate the outputs from trace and other circuit capacitances and limit the output currents, which could otherwise result in performance degradation. Only one driven input should be connected to the ADC output pins.

1.9 APPLICATION SCHEMATICS

The following figures show simple examples of using the ADC10080. Figure 5 shows a typical differentially driven input. Figure 6 shows a single ended application circuit.

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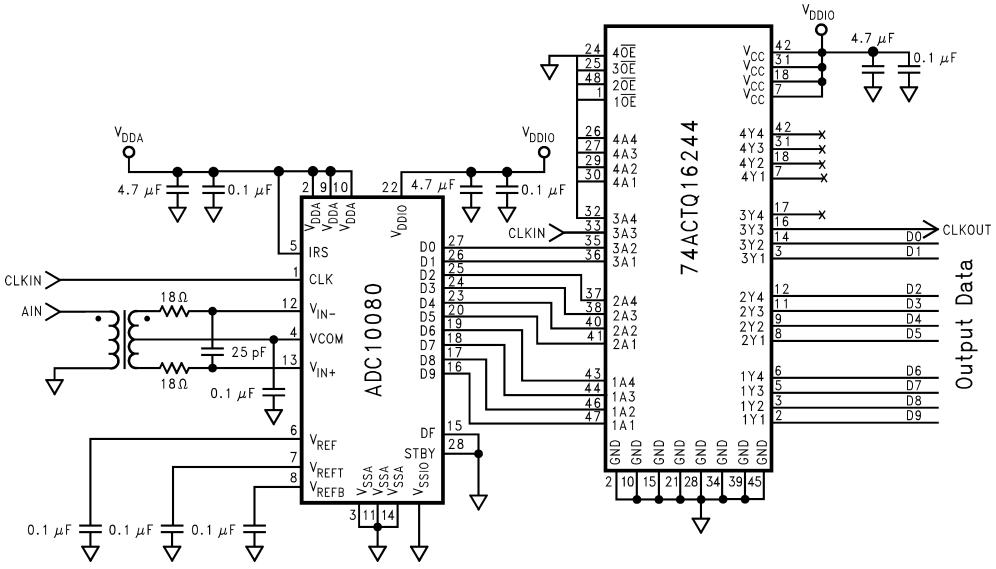


Figure 5. A Simple Application Using a Differential Driving Source

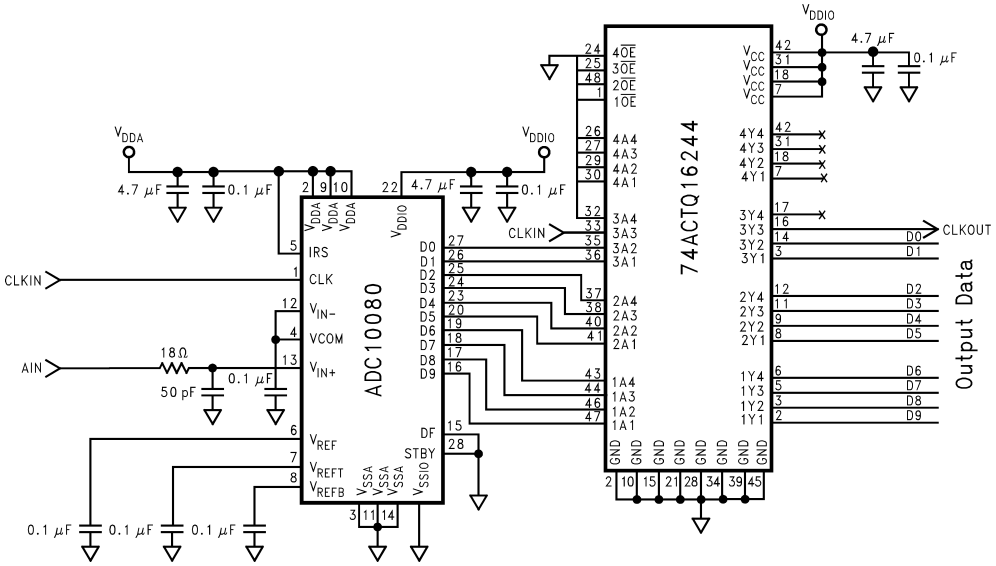


Figure 6. A Simple Application Using a Single Ended Driving Source

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)	Samples (Requires Login)
ADC10080CIMT/NOPB	ACTIVE	TSSOP	PW	28	48	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	
ADC10080CIMTX	ACTIVE	TSSOP	PW	28	2500	TBD	CU SNPB	Level-3-235C-168 HR	
ADC10080CIMTX/NOPB	ACTIVE	TSSOP	PW	28	2500	Green (RoHS & no Sb/Br)	CU SN	Level-3-260C-168 HR	

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

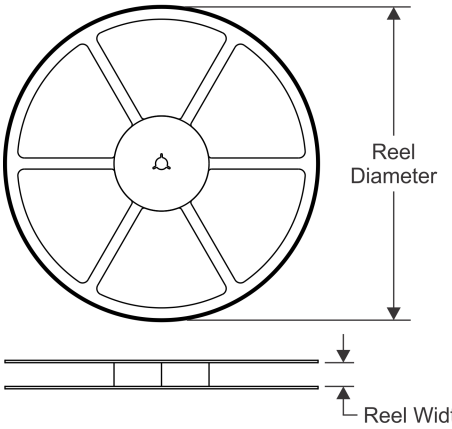
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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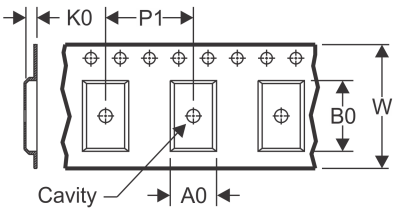
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TAPE AND REEL INFORMATION

REEL DIMENSIONS

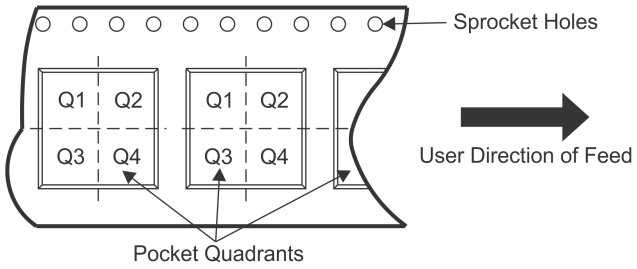


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

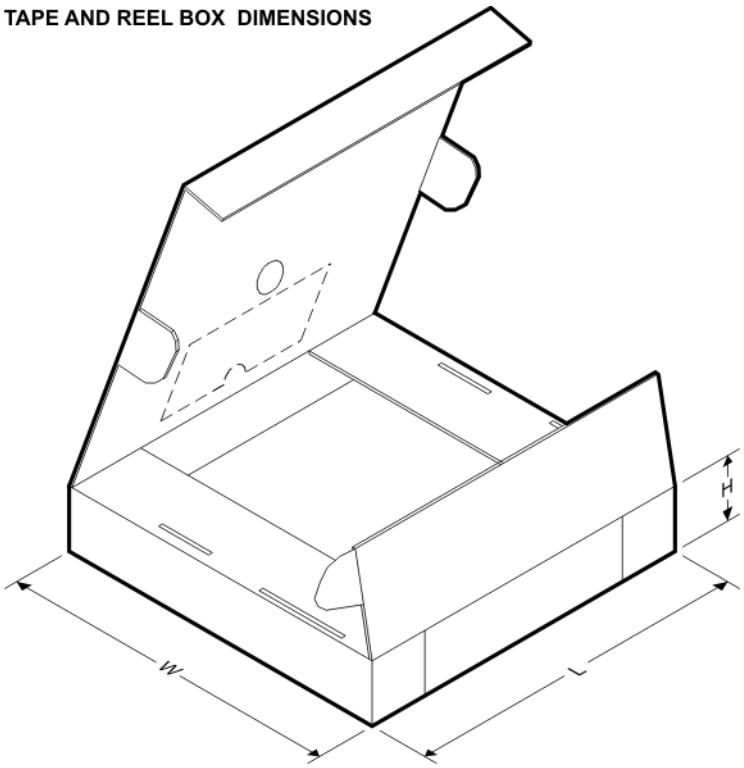
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADC10080CIMTX	TSSOP	PW	28	2500	330.0	16.4	6.8	10.2	1.6	8.0	16.0	Q1
ADC10080CIMTX/NOPB	TSSOP	PW	28	2500	330.0	16.4	6.8	10.2	1.6	8.0	16.0	Q1

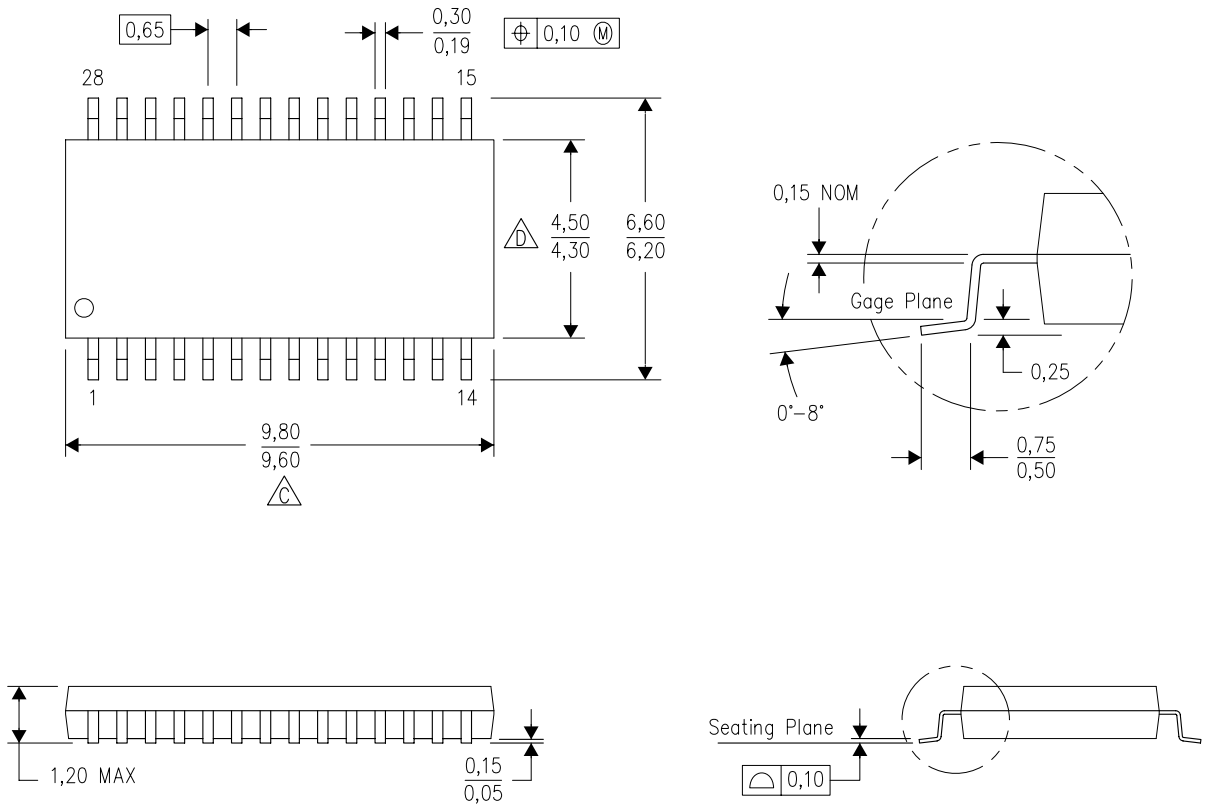
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADC10080CIMTX	TSSOP	PW	28	2500	358.0	343.0	63.0
ADC10080CIMTX/NOPB	TSSOP	PW	28	2500	358.0	343.0	63.0

PW (R–PDSO–G28) PLASTIC SMALL OUTLINE



4040064–7/G 02/11

NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
E. Falls within JEDEC MO–153

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